



NOTIFICATION OF ELECTRICAL VERIFICATION RESULTS

2019-02-18

QEM-CCR-1901-00691

DELTA ELECTRONICS INC

BMC

TI Device: TPS65910A31A1RSLR

TI Information – Selective Disclosure

*Important Note: The information provided herein may change if additional facts are discovered.

Notification of Electrical Verification Results:

Texas Instruments' BMC business entity has completed electrical verification for QEM-CCR-1901-00691. Verification results and next actions follow:

Customer Name:	DELTA ELECTRONICS INC	Customer Contact:	Carl Lin
Customer Site:	CHUNGLI INDUSTRIAL ZONE (TAIWAN)	Contact e-mail:	CARL.CK.LIN@deltaww.com
Customer Part #:		TI Device Type:	TPS65910A31A1RSLR
Customer Job #:		TI QEM Event #:	QEM-CCR-1901-00691
Event Type / Origin of Detection:	Prototype	Quantity of units returned:	1
Cust. Sent Date:		Event Open Date:	2019-01-17
Elect. Verification Complete Date:	2019-02-18	Current Task:	Publish Verification Report

TI QEM-CCR-1901-00691 includes 1 TI device(s) as follows:

The following returned TI device(s) were evaluated per the standard return flow process across the specified operating voltage and temperature ranges.

Identification of TI's Material						
TI's Part Number:	TPS65910A31A1RSLR					
Unit ID	Customer Unit ID	LTC	Assembly Lot #	Assembly Site	Fab Lot #	Fab Site
1						

Customer Problem Description:

Customer reported issue at: **Prototype**

The following customer provided issue description was extracted from the information submitted by the customer with the returned TI devices and was entered into TI's Quality Event Management System (QEM):

Issue type: Electrical | Issue type details: Pin48 output is abnormal. This pin in the datasheet is set to 11 for 3.3V, but the output is 4V.

DELTA prototype failure, returned from their end customer for pin48 output abnormal. This pin in the datasheet is set to 11 for 3.3V; for failure unit, output from pin48 is 4V. Failure rate: 1/30. Per check with customer, they copy their schematic from our reference design in <http://www.ti.com/lit/ug/swcu093f/swcu093f.pdf>.

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TI Problem Description:

The customer return was tested at TI utilizing the production test program suite to attempt to confirm the reported noncompliance and the following findings were noted:

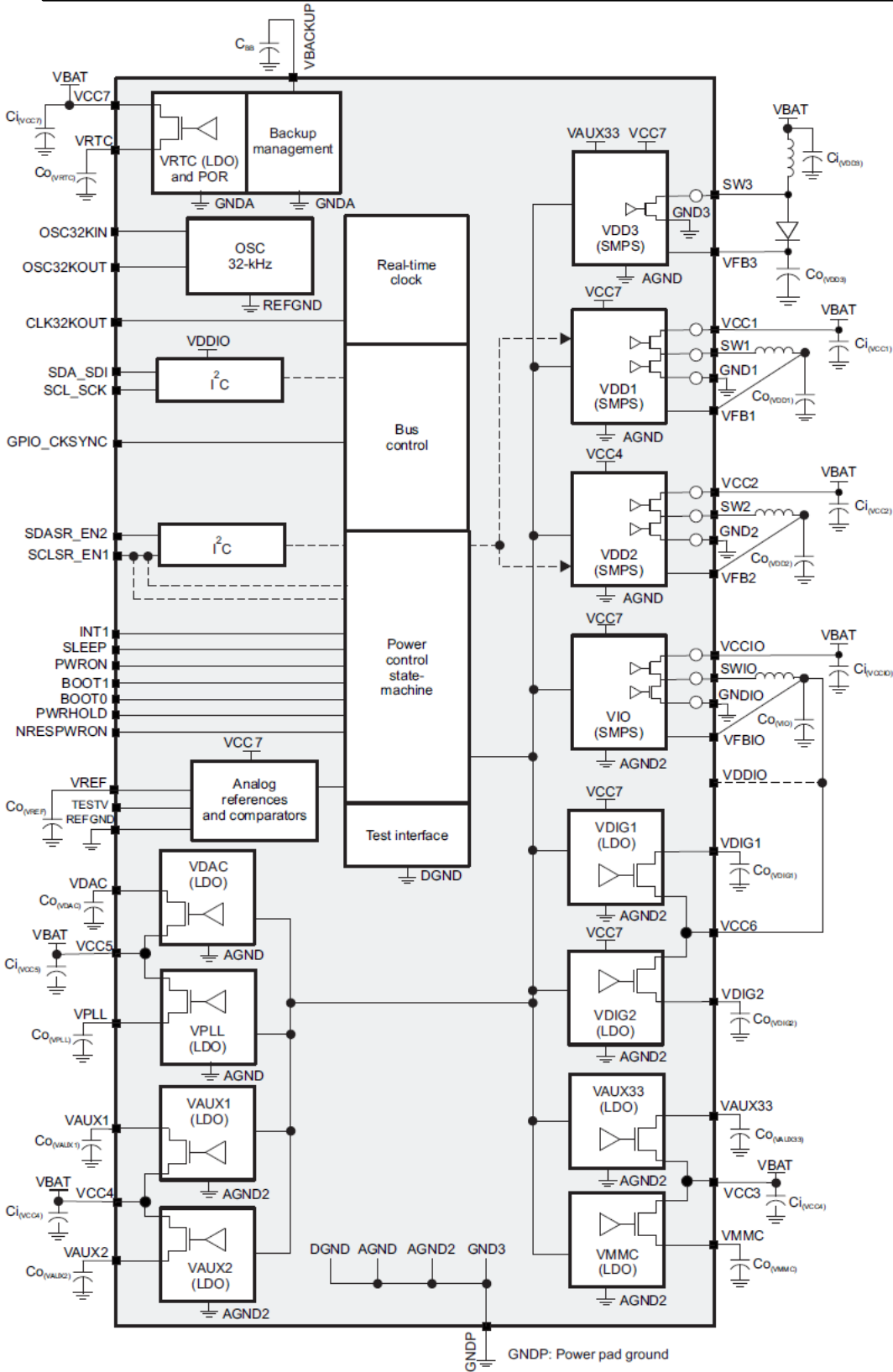
ATE Verification: The customer unit passed 10X loop testing at 25C on the VLCT18 tester

Bench Testing: The customer unit passed bench testing for pin 48 (VAUX2) output function. No abnormal output behavior was noticed during the bench analysis

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SWCS046-001

Figure 1-1. 48-QFN Top-Level Diagram

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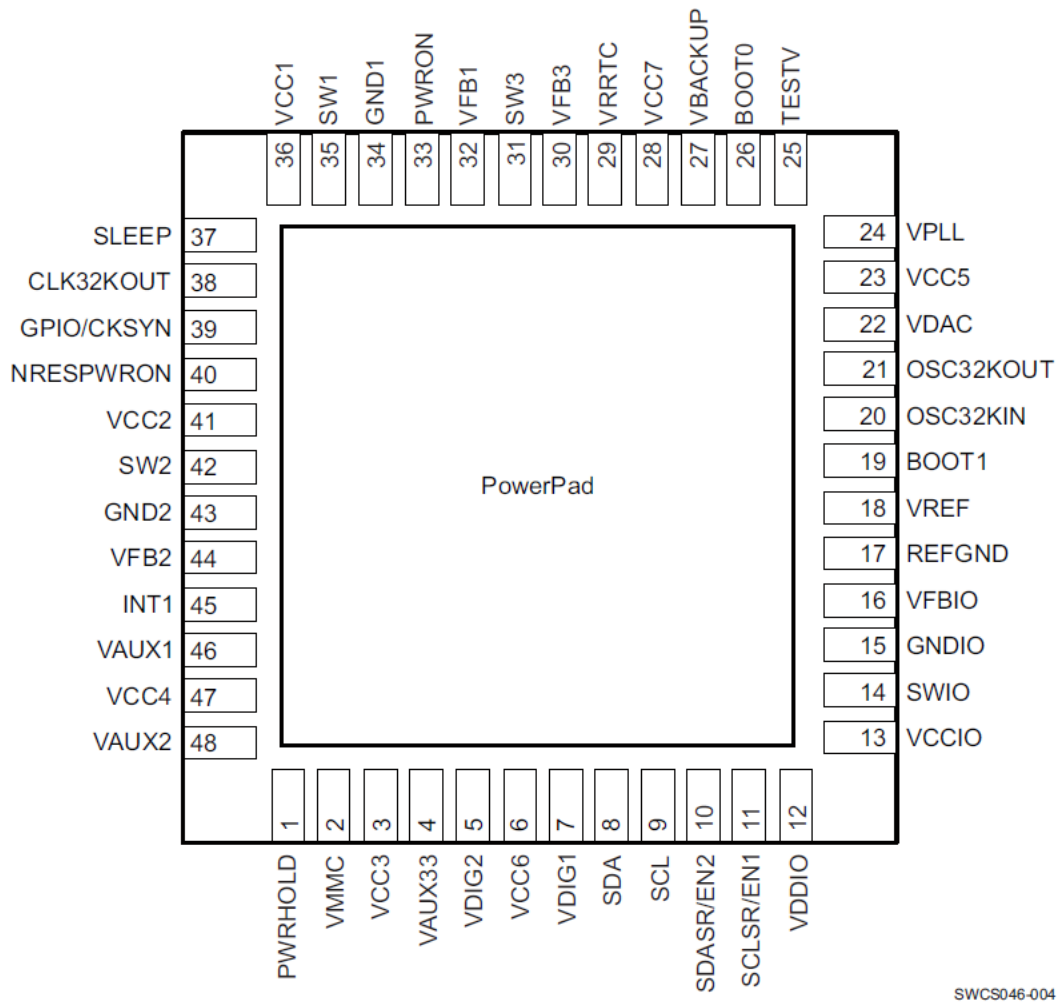


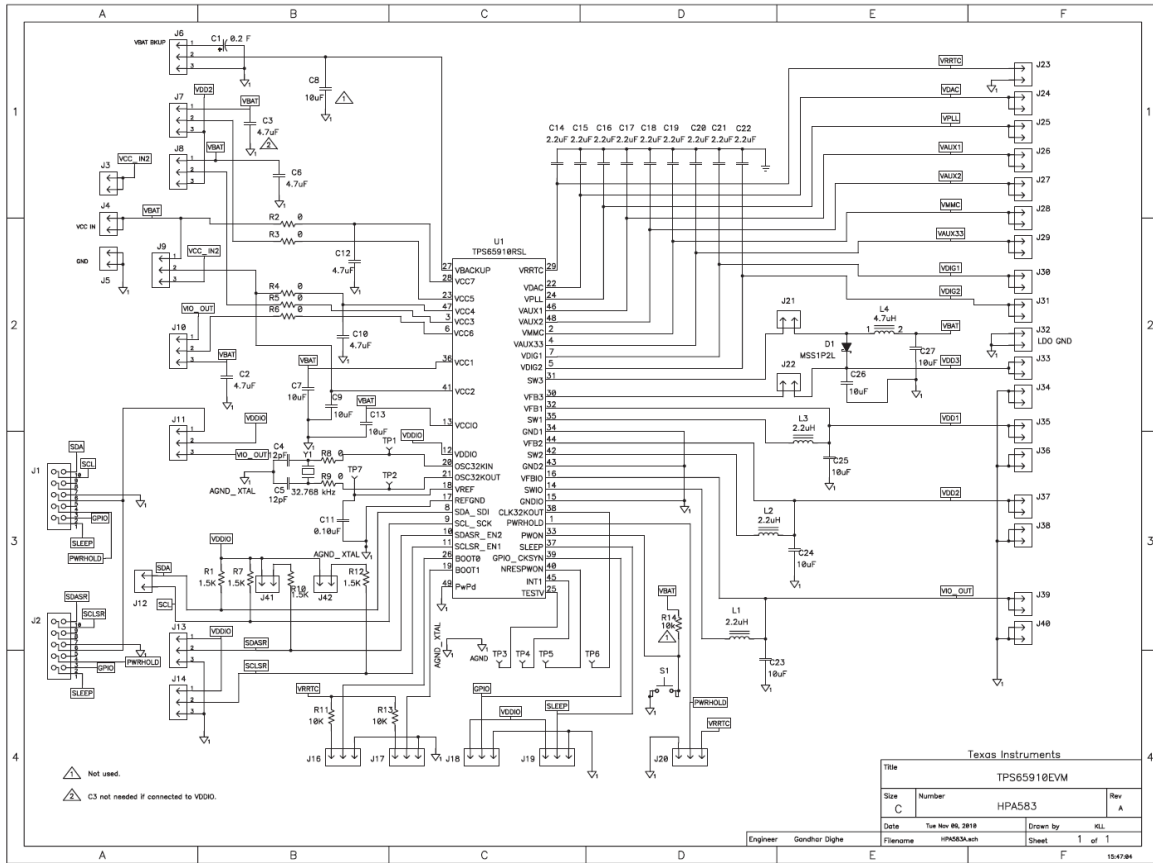
Figure 4-1. 48-QFN Top-View Pin Assignment

SWCS046-004

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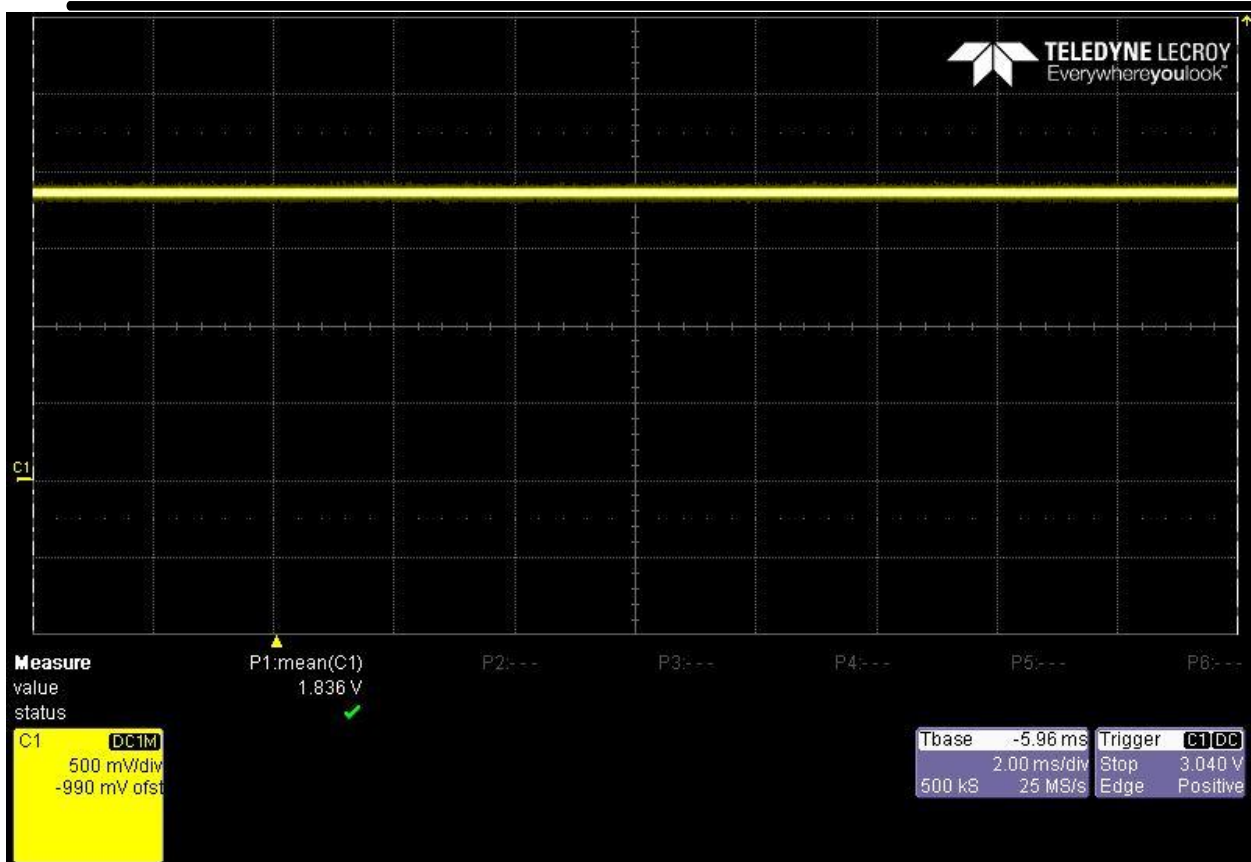
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Figure 1. TPS65910 EVM Schematic


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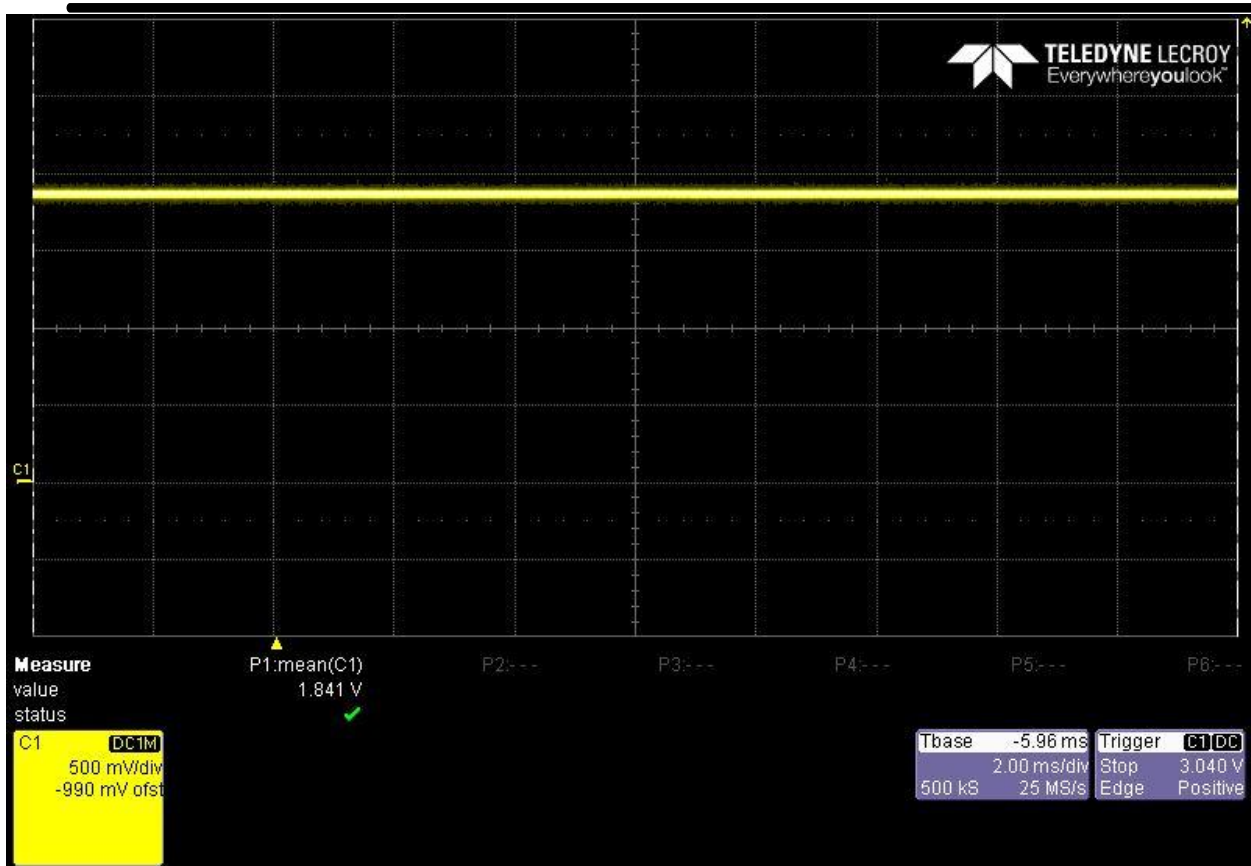


Good unit VAUX2 output waveform capture at 25C.

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Customer unit VAUX2 output waveform capture at 25C.

Actions / Disposition:

The reported fail signature was not verified, the unit passed ATE testing and no output abnormalities were noted during bench testing; Trouble Not Identified (TNI).

Contacts:

TI Team Member	Role	Email
Peggy Chen	Regional CQE	peggy.chen@ti.com
Olu Aderibigbe	Business CQE	olu@ti.com
Joe Nunez	Test Engineering	

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